TestConX China 2023

Machine Learning (ML) Applied to Test

IPS Constructive Solutions Generator with NLP Text Ranker

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Virtual - November 21-23, 2023



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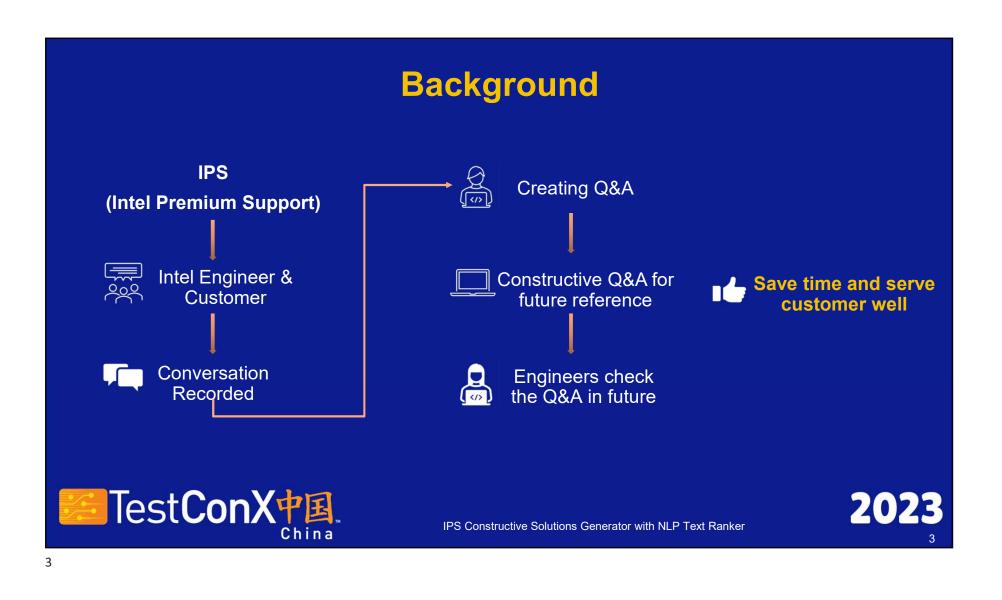
- Background
- Problem Statement
- Introduction
- Objectives
- Architecture Overview
- Methodology
- Results
- Summary
- Future Plan



IPS Constructive Solutions Generator with NLP Text Ranker



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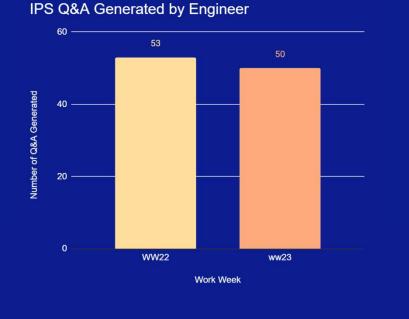


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Problem Statement

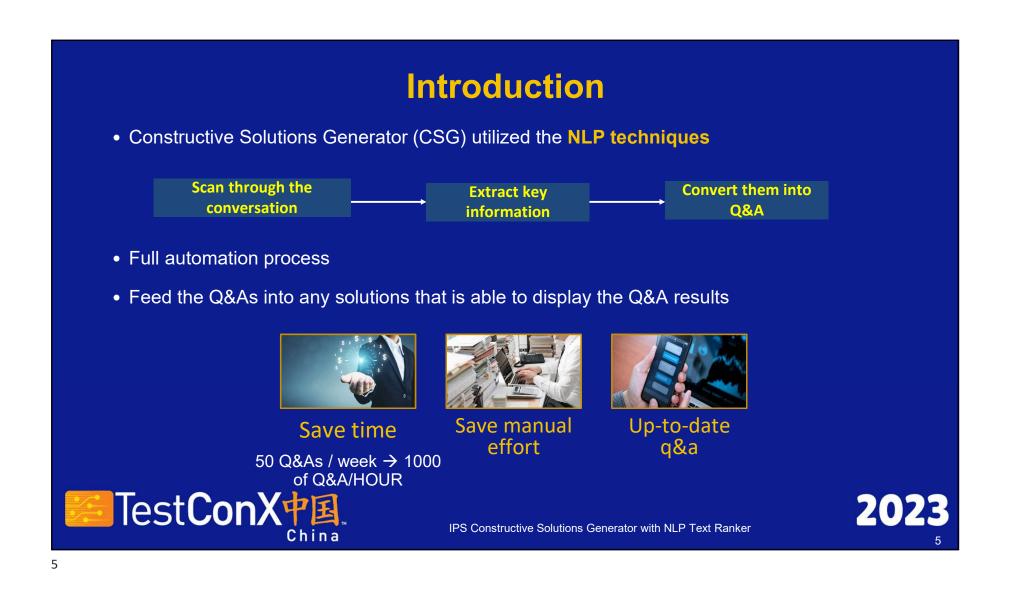
- Most of the IPS tickets contain lengthy and unconstructive conversation between Intel engineer and customer
- Engineers must review the whole conversation and look for the solution from it. Then, they manually create the Q&A
- Engineer spend one week time to create 50 Q&A
- Huge manual effort and time effort

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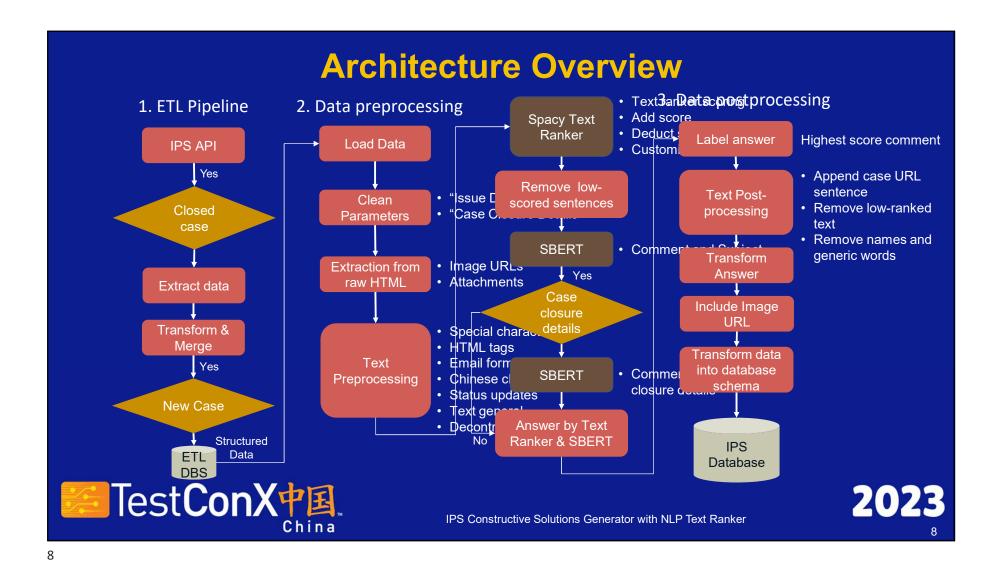


Session 1 Presentation 1

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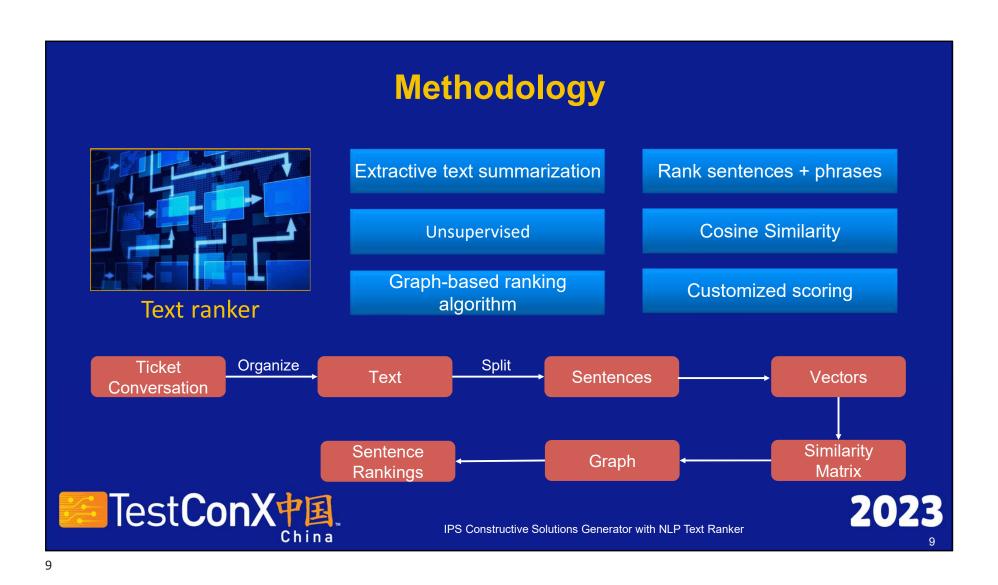
I guess you will provide the BOM list of the CRB, Could I have the expected release date? Developmentary * temperature * temper	CSG Transforming	Dutput in Chatbot I found this FAQ related to Reference Board - BOM list of Brightor city CRB Solutions: The Idaville LCC Brighton City schematic in Zuken format is available on the RDC document 626333. For more information, please refer to https://intel.lightning.force.com/lightning/r/Case/5003b00001L QxfAAF/view Case URL Link
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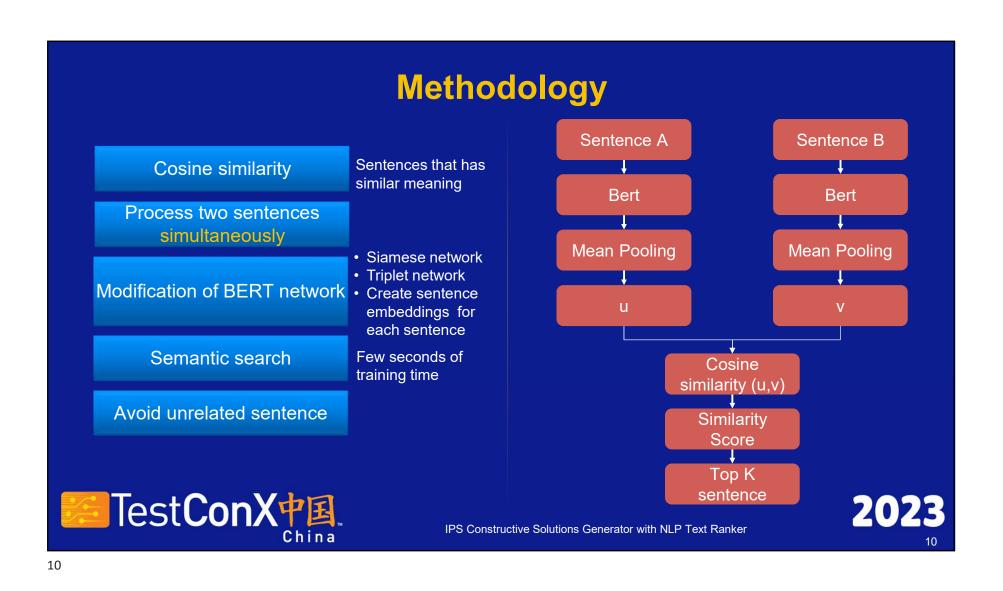


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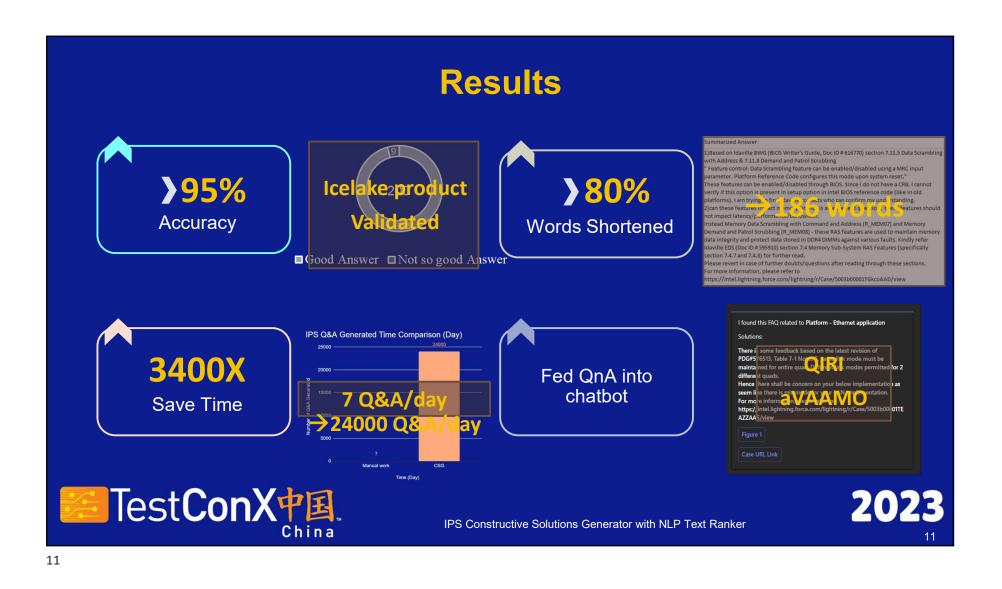
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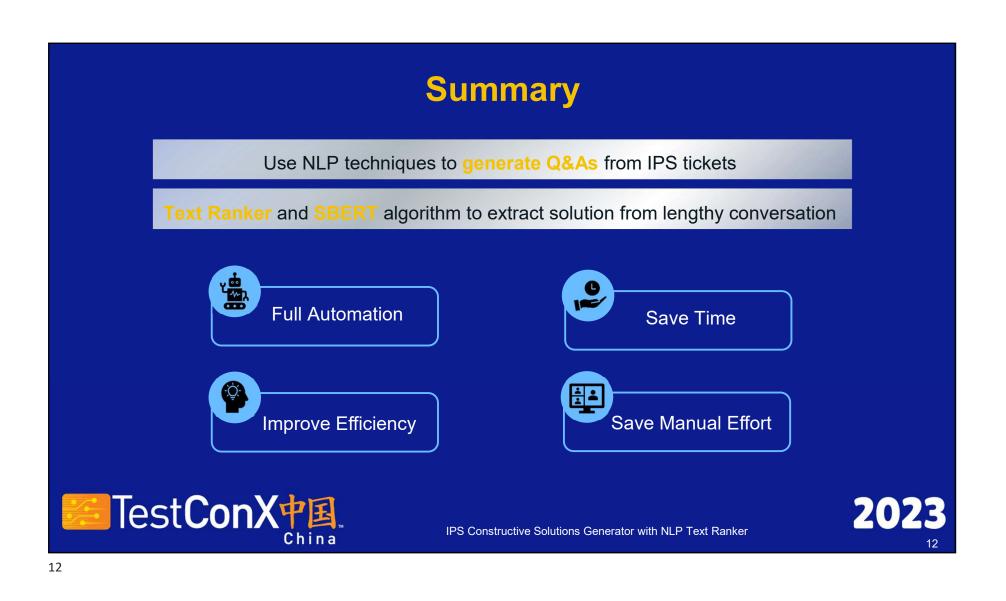
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Machine Learning (ML) Applied to Test

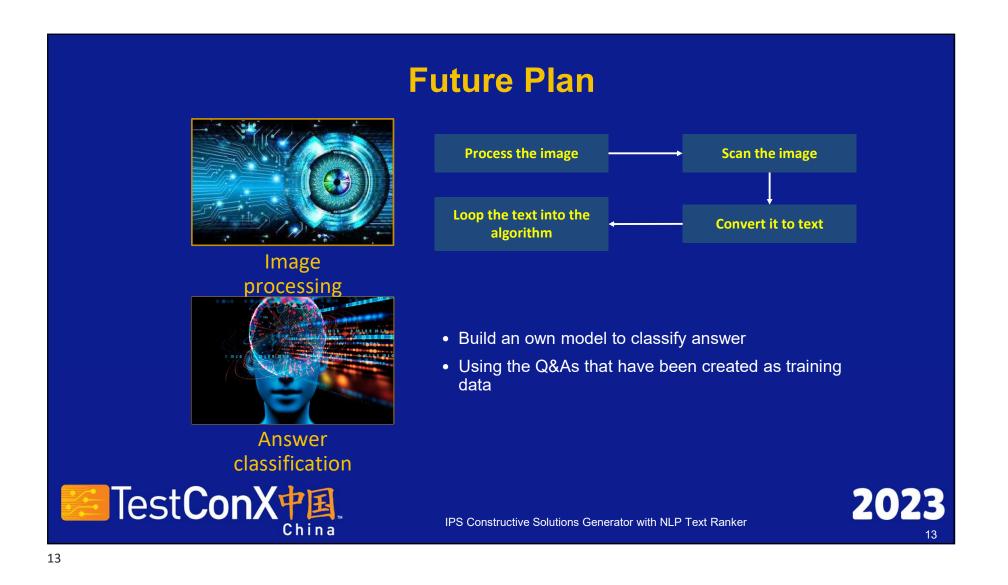


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